



# Test Report

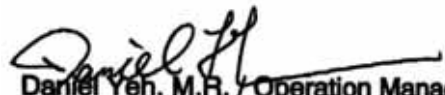
MERITEK ELECTRONICS CORPORATION  
11824 HAMDEN PLACE SANTA FE SPRINGS,  
CA 90670 U.S.A.

Report No. : CE/2004/C2896A  
Date : 2004/12/23  
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**The following merchandise was (were) submitted and identified by the client as :**

Type of Product : MULTILAYER CERAMIC CAPACITORS (AXIAL TYPE)  
Style/Item No : AXIAL TYPE Z5U SERIES  
Sample Received : 2004/12/15  
Testing Date : 2004/12/15 TO 2004/12/23

=====  
**Test Result** : - Please see the next page -

  
Daniel Yeh, M.R. / Operation Manager  
Signed for and on behalf of  
SGS TAIWAN LTD.



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## Test Result

PART NAME NO.1 : MIXED ALL PARTS (PLEASE REFER TO THE PHOTO ATTACHED)

Test Item (s):	Unit	Method	MDL	Result			
				No.1			
PBBs(Polybrominated biphenyls)(CAS NO:059536-65-1)	%	With reference to USEPA3540 or USEPA3550. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	N.D.			
PBBEs(PBDEs)(Polybrominated biphenyl ethers)	%	With reference to USEPA3540 or USEPA3550. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	N.D.			

Test Item (s):	Unit	Method	MDL	Result			
				No.1			
Chromium VI (Cr+6)	ppm	As per US EPA 7196A and US EPA 3060A.	2	N.D.			
Cadmium (Cd)	ppm	ICP-AES after as per EN 1122, method B:2001 or other acid digestion.	2	N.D.			
Mercury (Hg)	ppm	ICP-AES after as per US EPA 3052 or other acid digestion.	2	N.D.			
Lead (Pb)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.	2	49.0			

NOTE : (1) N.D. = Not detected (<MDL)  
(2) ppm = mg/kg  
(3) MDL = Method Detection Limit



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